Appl. No. 10/763,137 Amdt. Dated September 16, 2005 Reply to Office Action of June 16, 2005 Attorney Docket No. 88519.0002 Customer No.: 26021

## Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

## Listing of Claims:

- 1. (Original): A semiconductor light emitting device comprising a light emission layer, consisting of a GaN system semiconductor, which is interposed between an n type GaN system semiconductor layer and a p type GaN system semiconductor layer, wherein there is provided a Ga-doped  $Mg_zZn_{1-z}O$  ( $0\leq z<1$ ) electrode film.
- 2. (Original): The semiconductor light emitting device according to claim 1, characterized in that associated with a quantity of doped Ga, with which the  $Mg_zZn_{1-z}O$  ( $0\leq z<1$ ) electrode film is doped, wherein a carrier concentration is  $1\times 10^{10} \text{cm}^{-3}$  or more and  $5\times 10^{21} \text{cm}^{-3}$  or less.
- 3. (Original): The semiconductor light emitting device according to claim 1, characterized in that there is provided a metal electrode, which supplies an electric current to either the n type GaN system semiconductor layer or the p type GaN system semiconductor layer, and that said Ga-doped Mg₂Zn₁-₂O (0≤z<1) electrode film is formed between the n type GaN system semiconductor layer or the p type GaN system semiconductor layer, and the metal electrode.
- 4. (Original): The semiconductor light emitting device according to claim 3, characterized in that associated with a quantity of, the doped Ga, with which the  $Mg_2Zn_{1-z}O$  ( $0\leq z<1$ ) electrode film is doped, wherein a carrier concentration is  $1\times 10^{19} cm^{-3}$  or more and less than  $5\times 10^{21} cm^{-3}$ .

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- 5. (Previously Presented): The semiconductor light emitting device according to claim 1, characterized in that there is provided a metal electrode, which supplies an electric current to either the n type GaN system semiconductor layer or the p type GaN system semiconductor layer, and that the metal electrode and the Ga-doped  $Mg_zZn_{1-z}O$  ( $0 \le z < 1$ ) electrode film adjoin each other; and the metal electrode and the Ga-doped  $Mg_zZn_{1-z}O$  ( $0 \le z < 1$ ) electrode film are arranged so as to be contiguous to the face of the n type GaN system semiconductor layer or the p type GaN system semiconductor layer.
- 6. (Original): The semiconductor light emitting device according to claim 5, characterized in that associated with a quantity of the doped Ga, with which the  $Mg_2Zn_{1-z}O$  (0 $\leq$ z<1) electrode is doped, wherein a carrier concentration is  $1\times10^{19}cm^{-3}$  or more and less than  $5\times10^{21}cm^{-3}$ .
- 7. (Currently amended): A semiconductor light emitting device comprising a light emission layer, consisting of a GaN system semiconductor, which is interposed between a n type GaN system semiconductor layer and a p type GaN system semiconductor layer, wherein there is provided a B-doped Mg<sub>z</sub>Zn<sub>1-z</sub>O (0≤z<1) electrode film disposed on one of the GaN system semiconductor layers.
- 8. (Original): The semiconductor light emitting device according to claim 7, characterized in that associated with a quantity of the doped B, with which the  $Mg_zZn_{1-z}O$  (0 $\leq$ z<1) electrode is doped, wherein a carrier concentration is  $1\times10^{19}cm^{-3}$  or more and less than  $5\times10^{21}cm^{-3}$ .
- 9. (Original): The semiconductor light emitting device according to claim 7, characterized in that there is provided a metal electrode, which supplies an electric current to either the n type GaN system semiconductor layer or the p type

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GaN system semiconductor layer, wherein said B-doped Mg<sub>z</sub>Zn<sub>1-z</sub>O (0≤2<1) electrode film is formed between the n type GaN system semiconductor layer or the p type GaN system semiconductor layer, and the metal electrode.

- 10. (Original): The semiconductor light emitting device according to claim 9, characterized in that associated with a quantity of the doped B, with which the  $Mg_zZn_{1-z}O$  (0 $\leq z<1$ ) electrode is doped, wherein a carrier concentration is  $1\times10^{19}$ cm<sup>-3</sup> or more and less than  $5\times10^{21}$ cm<sup>-3</sup>.
- 11. (Previously Presented): The semiconductor light emitting device according to claim 7, characterized in that there is provided a metal electrode, which supplies an electric current to either the n type GaN system semiconductor layer or the p type GaN system semiconductor layer, wherein the metal electrode and the B-doped Mg<sub>2</sub>Zn<sub>1-2</sub>O (0≤z<1) electrode film adjoin each other and the metal electrode and the B-doped Mg<sub>2</sub>Zn<sub>1-2</sub>O (0≤z<1) electrode film are arranged so as to be contiguous to the face of the n type GaN system semiconductor layer or the p type GaN system semiconductor layer.
- 12. (Original): The semiconductor light emitting device according to claim 11, characterized in that associated with a quantity of the doped B, with which the  $Mg_zZn_{1-z}O$  (0 $\leq$ z<1) electrode is doped, wherein a carrier concentration is  $1\times10^{19}cm^{-3}$  or more and less than  $5\times10^{21}cm^{-3}$ .